

## EAST Search History

| Ref # | Hits   | Search Query  | DBs   | Default Operator | Plurals | Time Stamp       |
|-------|--------|---|---|------------------|---------|------------------|
| L1    | 462748 | wafer\$1  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/07/20 13:23 |
| L2    | 437    | 1 and (( insufficient or available or enough or sufficient ) near3 (spare or spares or redundant))        | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/07/20 13:34 |
| L3    | 683    | ( id or identif\$4 or identificat\$4 ) near7 ( spare or spares or redundant ) near5 used                  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/07/20 13:28 |
| L4    | 36     | 3 near7 ( row\$1 or column\$1 )   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/07/20 13:28 |
| L5    | 21     | 3 near7 repair\$4   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/07/20 13:29 |
| L6    | 35     | good with unrepairable  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/07/20 13:29 |
| L7    | 223    | (( mcm or multi adj chip adj module ) and (( bad or defective or good) near7 (repair\$4 or unrepair\$ ))) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/07/20 13:32 |
| L8    | 1480   | (( dice or wafer ) adj ( map\$1 or mapping ))   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | OFF     | 2006/07/20 13:33 |

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|     |     |  |   |    |     |                  |
|-----|-----|--|---|----|-----|------------------|
| L9  | 5   | 8 and 3  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/07/20 13:33 |
| L10 | 6   | 8 and (( insufficient or available or<br>enough or sufficient ) near3 (spare or<br>spares or redundant)) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/07/20 13:34 |
| L12 | 223 | (( test\$3 or retest\$3 ) near7 (bad or<br>unrepairable or defective ) ) and 8                           | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/07/20 13:36 |
| L13 | 53  | (( inefficient or redundant or repeat\$3<br>) near7 (bad or unrepairable or<br>defective ) ) and 8       | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/07/20 13:37 |

**EAST Search History**

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|-------|------|---|----------|------------------|---------|------------------|
| L1    | 1340 | (( id or identif\$4 or identificat\$4 ) and repair\$3 ).clm.                            | US-PGPUB | OR               | OFF     | 2006/07/20 13:53 |
| L2    | 386  | (( id or identif\$4 or identificat\$4 ) with repair\$3 ).clm.                           | US-PGPUB | OR               | OFF     | 2006/07/20 13:53 |
| L3    | 8    | 2 and ( identification adj code\$1 ).clm.   | US-PGPUB | OR               | OFF     | 2006/07/20 13:54 |
| L4    | 557  | ( repair\$3 with ( memory or memeories or wafer or dice or ic or semiconductor ) ).clm. | US-PGPUB | OR               | OFF     | 2006/07/20 13:56 |
| L5    | 74   | 2 and 4   | US-PGPUB | OR               | OFF     | 2006/07/20 13:56 |
| L6    | 150  | 1 and 4   | US-PGPUB | OR               | OFF     | 2006/07/20 13:56 |
| L7    | 86   | 6 and read\$4.clm.  | US-PGPUB | OR               | OFF     | 2006/07/20 13:57 |
| L8    | 43   | 7 not 5   | US-PGPUB | OR               | OFF     | 2006/07/20 13:57 |